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	Application No.	Applicant(s)
•	10/740,013	SERGOYAN ET AL.
Notice of Allowability	Examiner	Art Unit
	Walter Benson	2858
The MAILING DATE of this communication appears All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIOF the Office or upon petition by the applicant. See 37 CFR 1.313	ears on the cover sheet with (OR REMAINS) CLOSED in the or other appropriate communi GHTS. This application is sub- and MPEP 1308.	nis application. If not included cation will be mailed in due course. THIS
1. This communication is responsive to <u>Amendment filed</u> , 5/0	<u>12/05</u> .	•
2. The allowed claim(s) is/are <u>1-29</u> .		
3. \boxtimes The drawings filed on <u>02 May 2005</u> are accepted by the Ex	kaminer.	
 4. Acknowledgment is made of a claim for foreign priority unally All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority documents have International Bureau (PCT Rule 17.2(a)). * Certified copies not received: 	been received. been received in Application	No
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		reply complying with the requirements
5. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give		
6. ☐ CORRECTED DRAWINGS (as "replacement sheets") mus (a) ☐ including changes required by the Notice of Draftspers 1) ☐ hereto or 2) ☐ to Paper No./Mail Date (b) ☐ including changes required by the attached Examiner's Paper No./Mail Date	on's Patent Drawing Review (s Amendment / Comment or in	the Office action of
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in t		
7. DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT.		
Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)	6. ☐ Interview Sum	
3. Information Disclosure Statements (PTO-1449 or PTO/SB/0	8), 7. ⊠ Examiner's Ar	ail Date nendment/Comment
Paper No./Mail Date 4. Examiner's Comment Regarding Requirement for Deposit	8. ☐ Examiner's St	atement of Reasons for Allowance
of Biological Material	9. Other	
Walter Benow	·	

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EXAMINER'S AMENDMENT

- 1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.
- 2. Authorization for this examiner's amendment was given in a telephone interview with Scott T. Gray, Reg. No. 48,891 on 6/30/05.
- 3. The application [claims, 5/02/05] has been amended as follows:
 - a. In claim 1, line 10, inserted --, to thereby determine a measured thickness of the non-conductive coating on the semi-conductor substrate. after "plates"

Allowable Subject Matter

4. Claims 1-29 are allowed over the prior art.

The prior art of record fails to teach in combination as claimed a system for measuring a thickness of a non-conductive coating on a semi-conductive substrate. The system including a first conducting plate adapted to be placed in contact with a non-conductive coating on a semi-conductive substrate at a first location and a second conducting plate adapted to be placed in contact with the non-conductive coating at a second location. The

system measures a thickness of a non-conductive coating on a semi-conductive substrate. The system includes a capacitance meter electrically connected to the first and second conducting plates, where the capacitance meter is adapted to measure a capacitance value of the non-conductive coating in combination with the semi-conductive substrate between the first and second conducting plates, to thereby determine a measured thickness of the non-conductive coating on the semiconductor substrate. A change in capacitance from a known capacitance of a semi-conductive component without the non-conductive material and measured capacitance with the non-conductive component is directly proportional to non-conductive coating thickness.

Prior Art Made of Record

- 1. The prior art made of record and not relied upon is considered pertinent to applicant=s disclosure
- A. Koch (US Patent No. 5,293,132) discloses a method and apparatus for measuring thickness of a non-conductive coating on a ferromagnetic and non-ferromagnetic substrates;
- B. Baer (US Patent No. 5,093,626) discloses a device for measuring a conductive coating on a non-conductive substrate.

The closest prior art fails to anticipate or render Applicant's limitation above obvious.

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Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Walter Benson whose telephone number is (571) 272-2227. The examiner can normally be reached on Mon to Fri 6:30 AM to 4:00 PM.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Edward Lefkowitz can be reached on (571) 272-2180. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Walter Benson
Patent Examiner

July 6, 2005

